Search Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/724,101	OHMI ET AL.	
Examiner	Art Unit	
Jennifer A. Leuna	1764	•

SEARCHED				
Class	Subclass	Date	Examiner	
422	187-190,	6/22/05	MAL	
	211,212,	}	١	
	220,222			
	168,169,			
	171,176,	•		
	177,180			
	198			
423	580.			
376	300,301			
976	D16.271		\	
165	80.3	V	7	

INTERFERENCE SEARCHED				
Subclass	Date	Examiner		
	Subclass	Subclass Date		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Inventor Search. assignee search.	6/22/05	PAL		
su search for parent, 09/773605	6/22/05	<i>a</i> nc		
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